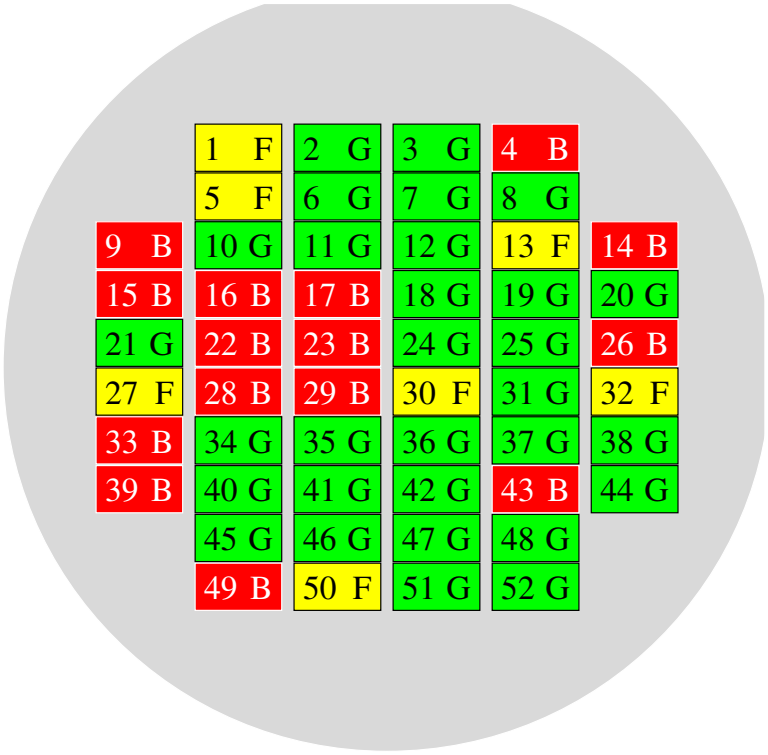
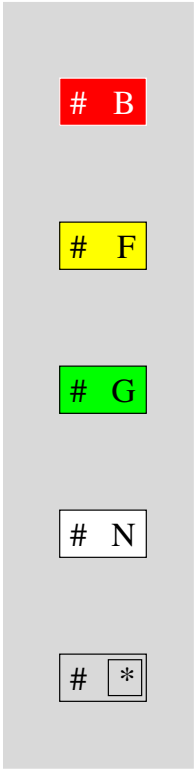
Die quality map for wafer 30 s/n: 21316-06-13 (not backplated)

Date: 11/02/98





Bad die

Fair die

Good die

No info

Manually tagged